

Product Change Notification: DSNO-11CVSI654

Date:

17-Jun-2025

Product Category:

Automotive LED Drivers, General Purpose LED Drivers

Notification Subject:

CCB 7630 Initial Notice: Qualification of ATP7 as an additional assembly site for AT9919K7-GVAO, HV9918K7-G, HV9919BK7-G, AT9919K7-G and HV9967BK7-G catalog part numbers (CPN) available in 8L WDFN (3x3x0.8mm) package.

Affected CPNs:

DSNO-11CVSI654_Affected_CPN_06172025.pdf DSNO-11CVSI654_Affected_CPN_06172025.csv

PCN Status: Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ATP7 as an additional assembly site for AT9919K7-GVAO, HV9918K7-G, HV9919BK7-G, AT9919K7-G and HV9967BK7-G catalog part numbers (CPN) available in 8L WDFN (3x3x0.8mm) package.

Pre and Post Summary Changes:

	Pre Change	Post Change					
Assembly Site	Carsem (Suzhou) (CARC)	Carsem (Suzhou) (CARC)	Amkor Technology Philippines (P3/P4), INC. (ATP7)				
Wire Material	Au	Au	CuPdAu				
Die Attach Material	QMI519	QMI519	AP4300				

Molding Compound Material	G770HD	G770HD	G631BQF				
Lead-Frame Material	C194	C194	C194				
Lead-Frame Paddle Size	104x75 mils	104x75 mils	106x75 mils				
DAP Surface Prep	Ag Spot	Ag Spot	Ring Ag				

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ATP7 as an additional

assembly site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: December 2025

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Timetable Summary:

	June 2025				>	December 2025					
Work Week	23	24	25	26	27		49	50	51	52	53
Initial PCN Issue Date			X								
Qual Report Availability											X
Final PCN Issue Date											X

Method to Identify Change: Traceability Code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN # Qual Plan.

Revision History: June 17, 2025: Issued initial notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_DSNO-11CVSI654_Pre and Post Change Summary.pdf PCN_DSNO-11CVSI654_Qual Plan.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> <u>home page</u> select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

DSNO-11CVSI654 - CCB 7630 Initial Notice: Qualification of ATP7 as an additional assembly site for AT9919K7-GVAO, HV9918K7-G, HV9919BK7-G, AT9919K7-G and HV9967BK7-G catalog part numbers (CPN) available in 8L WDFN (3x3x0.8mm) package.

Affected Catalog Part Numbers (CPN)

AT9919K7-GVAO

HV9918K7-G

HV9919BK7-G

AT9919K7-G

HV9967BK7-G

Date: Thursday, June 12, 2025

CCB 7630

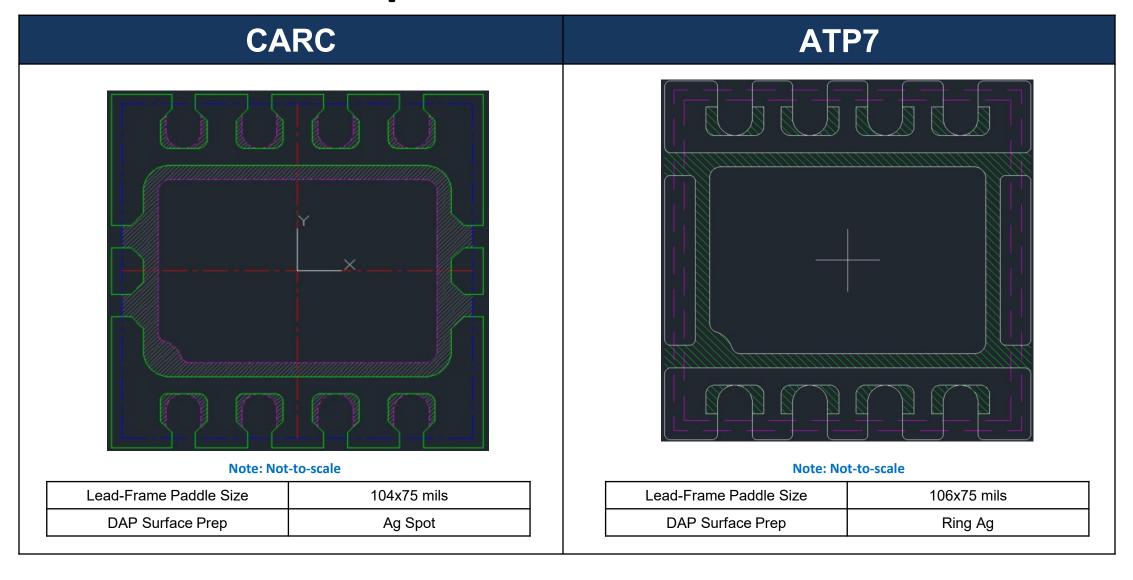
Pre and Post Change Summary PCN #: DSNO-11CVSI654



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Lead-Frame Comparison





QUALIFICATION PLAN SUMMARY

PCN #: DSNO-11CVSI654

Date: May 22, 2025

Qualification of ATP7 as an additional assembly site for AT9919K7-GVAO, HV9918K7-G, HV9919BK7-G, AT9919K7-G and HV9967BK7-G catalog part numbers (CPN) available in 8L WDFN (3x3x0.8mm) package.

Purpose:

Qualification of ATP7 as an additional assembly site for AT9919K7-GVAO, HV9918K7-G, HV9919BK7-G, AT9919K7-G and HV9967BK7-G catalog part numbers (CPN) available in 8L WDFN (3x3x0.8mm) package.

CCB No.: 7630

	Assembly site	ATP7				
	BD Number	TBD				
	MP Code (MPC)	VAGAxxxx VAKA1xxx				
Misc.	Part Number (CPN)	Various				
	MSL information	MSL-1, 260'C				
	Assembly Shipping Media (T/R, Tube/Tray)	Cannister				
	Base Quantity Multiple (BQM)	3,300				
	Reliability Site	MTAI				
	Paddle size	106X75				
	Material	C194				
	DAP Surface Prep	Ring Ag				
	Treatment	Rough				
Lead-Frame	Process	Etch				
<u>Leau-Fraille</u>	Lead-lock	Yes (Half Etch)				
	Part Number	101431257				
	Lead Plating	Matte Sn				
	Strip Size	70x250mm				
	Strip Density	1224				
Bond Wire	Material	CuPdAu				
Die Attach	Part Number	AP4300				
<u>Die Attach</u>	Conductive	Yes				
<u>MC</u>	Part Number	G631BQF				
	Package Type	WDFN				
<u>PKG</u>	Pin/Ball Count	8				
	PKG width/size	3x3x0.8mm				

Test Name	Conditions	Reliability Stress Read Point Grade 1: -40°C to +125°C (MCHP E Temp)	Pre & Post Reliability Stress Test Temperature Grade 1: -40°C to +125°C (MCHP E Temp)	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Standard Pb-free Solderability	J-STD-002D; Perform 8 hours of steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.			22	5	1	27	>95% lead coverage	5	Standard Pb-free solderability is the requirement. *Additional Requirement: If burn-in screening is normally performed on the device before shipment, samples for SD must first undergo burn-in or equivalent high temperature baking.
Wire Bond Pull - WBP	Mil. Std. 883-2011			5	0	1	5	0 fails after TC	5	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001			5	0	1	5	0	5	30 bonds from a min. 5 devices.
Physical Dimensions	Measure per JESD22 B100 and B108			10	0	3	30	0	5	
External Visual	Mil. Std. 883-2009/2010			All devices prior to submission for qualification testing	0	3	ALL	0	5	
HTSL (High Temp Storage Life)	JESD22-A103 +125°C, +150°C or +175°C 2x Stress	1st Readpoint: Grade 1: 500 hrs (+175°C) or 1000 hrs (150°C) 2nd Readpoint: Grade 1: 1000 hrs (+175°C) or 2000 hrs (150°C)	Grade 1: +25°C, +125°C	45	5	3	150	0	21 - 167	Perform per the requirements in AEC-Q100/Q101. Spares should be properly identified.
Preconditioning - Required for surface mount devices	J-STD-020 JESD22-A113 MSL-1, 260°C +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type.		Grade 1: +25°C	231	15	3	738	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
HAST	JESD22-A101 or A110 +130°C/85% RH for 96 hrs or +110°C/85%RH for 264 hrs	1st Readpoint: Grade 1: 96 hrs (+130°C/85% RH) or 264 hrs (+110°C/85%RH) 2nd Readpoint: Grade 1: 192 hrs (+130°C/85% RH) or 528 hrs (+110°C/85%RH)	Grade 1: +25°C, +125°C	77	5	3	246	0	10 - 22	Perform per the requirements in AEC-2006. Spares should be properly identified. Use the parts which have gone through Pre- conditioning.
uhast	JESD22-A102, A118, or A101 +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs	Grade 1: 96 hrs (+130°C/85% RH) or 264 hrs (+110°C/85% RH)	Grade 1: +25°C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Preconditioning.
Temp Cycle	JESD22-A104 -55°C to +125°C, -55°C to +150°C 2x Stress	1st Readpoint: Grade 1: 1000 cycles (-55°C to +150°C) 2nd Readpoint: Grade 1: 2000 cycles (-55°C to +150°C)	Grade 1: +25°C, +125°C	77	5	3	246	0	15 - 120	Perform per the requirements in AEC-Q006. Spares should be properly identified. Use the parts which have gone through Pre- conditioning.
Wire Bond Integrity (AEC-Q006 Requirements) +14:1714:15	AEC-Q006									